

Technical Tracks & Topics

5G/Millimeter Wave

- 5G
- WiGig
- Wideband Radio Frequency (RF)

High Performance Digital

- High Performance Computing
- High End Mobile Processors
- Power Distribution

Factory Automation

- Methodologies, tools, and best practices that address the challenges in device production
- Improving test data quality
- Reducing test excursion
- Improving OEE, yield and uptime
- Improving cost management.

Parametric Test

- Cost of test reduction
- Throughput improvements
- Novel test techniques for parametric test or WLR
- Dynamic and predictive test flows
- Platform correlation techniques

Hardware & Software Design Integration

- Utilizing the latest hardware or software features
- Test Cells
- New test system enhancements

Test Methodologies

- Supporting standards & protocols
- Solutions for the latest testing challenges
- CoT reduction
- Throughput improvements
- Time-to-market improvements

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- Automotive controllers, Microcontrollers & Power ICs
- Sensor cameras
- Massive parallelism
- System level testing for SiP
- Display driver testing

Artificial Intelligence:

- AI Aided testing
- AI Generated Code
- Smart Data Innovation & Big Data Analytics
- Solutions addressing Artificial Intelligence

Hot Topics:

- New Market Drivers & future trends
- Secure ID and Cyber Security
- Secure Cloud
- Video streaming/telepresence
- IoT (Wearables, Sensors, Smart Cities & Homes)

Device/System Level Test

- Specific procedures
- MIMO testing
- Next-generation Embedded Processors
- Broadband fiber to the home
- Testing ICs for autonomous vehicles
- Multi-chip system-in-package devices